

Notice of References Cited	Application/Control No. 10/015,899	Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner Satish S. Rampuria	Art Unit 2124	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,381,565	04-2002	Nakamura, Yuichi	703/28
	B	US-6,453,435	09-2002	Limon et al.	714/724
	C	US-6,421,071	07-2002	Harrison, Michael John	715/787
	D	US-4,185,298 A	01-1980	Billet et al.	348/129
	E	US-4,872,052 A	10-1989	Liudzius et al.	348/126
	F	US-5,323,108 A	06-1994	Marker et al.	324/158.1
	G	US-5,561,696 A	10-1996	Adams et al.	378/58
	H	US-5,687,209 A	11-1997	Adams, John A.	378/22
	I	US-5,781,447 A	07-1998	Gerdes, Henry D.	716/15
	J	US-6,042,614 A	03-2000	Davidson et al.	717/116
	K	US-6,097,202 A	08-2000	Takahashi, Tadashi	324/761
	L	US-6,144,954 A	11-2000	Li, Chou H.	706/62
	M	US-6,158,119 A	12-2000	Crist et al.	29/840

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09-081416	03-1997	Japan	Kenji	G06F 11/28
	O	JP 09-006702	01-1997	Japan	Kunio	G06F 13/10
	P	JP10-301803	11-1998	Japan	Yoshimi	G06F 11/28
	Q	JP 06-139101	05-1994	Japan	Weinbaum	G06F 11/22
	R	JP 10-340201	12-1998	Japan	Yoshiyuki	G06F 11/22
	S	JP 05-133992	05-1993	Japan	Katsuhide	G06R 31/02
	T	JP 11-118889	04-1999	Japan	Yoshihiko	G01R 31/3183

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Raghunathan et al., A content based retrieval engine for circuit board inspection, IEEE, 1999, Pages:104 - 108 vol.1
✓	V	Mostafa et al., Design of an inspection system for electrical characteristics of a PC board, IEEE, 6-9 Nov. 1993, Pages:720 - 724
✓	W	Sen-Tarng et al., A software metric combination model for software reuse, IEEE, 2-4 Dec. 1998, Pages:70 - 77
✓	X	Li-Ren et al., A Gauss-elimination based PRPG for combinational circuits, IEEE, 6-9 March 1995, Pages:212 - 216

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/015,899	Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
	Examiner Satish S. Rampuria	Art Unit 2124	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,195,774 B1	02-2001	Jacobson, Neil G.	714/727
	B	US-6,198,529 B1	03-2001	Clark et al.	356/237.5
	C	US-6,408,432 B1	06-2002	Herrmann et al.	717/139
	D	US-6,571,386 B1	05-2003	Figurin et al.	717/154
	E	US-2002/0105353 A1	08-2002	Mori et al.	324/765
	F	US-2003/0033406 A1	02-2003	John et al.	709/224
	G	US-2004/0163241 A1	08-2004	White, William H.	029/832
	H	US-6,401,220	06-2002	Grey et al.	714/33
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Rolince et al., Next generation functional test program development system, IEEE , 18-21 Sept. 2000, Pages:125 - 128
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.